



Product/Process Change Notice - PCN 22_0088 Rev. -

Analog Devices, Inc. One Analog Way, Wilmington, MA 01887

This notice is to inform you of a change that will be made to certain ADI products (see Appendix A) that you may have purchased in the last 2 years. **Any inquiries or requests with this PCN (additional data or samples) must be sent to ADI within 30 days of publication date.** ADI contact information is listed below.

PCN Title: LTC2979 Datasheet Limit Change

Publication Date: 27-Apr-2022

Effectivity Date: 30-Jul-2022 *(the earliest date that a customer could expect to receive changed material)*

Revision Description:

Initial Release

Description Of Change:

Please be advised that Analog Devices has made minor changes to the LTC2979 product datasheet to facilitate improvement in manufacturing capability. The changes are shown on the attached pages of the marked-up datasheet.

Electrical Characteristics table changes (pages 5 of datasheet):

1. Output Sinking Current at condition: Weak Pull-Down Enabled minimum spec limit changed from 33uA to 28uA. Typical value changed from 50uA to 43uA.
2. Output Sinking Current at condition: Strong Pulldown Enabled temperature condition changed from Tri-temperature to Room temperature only. Also, remove the minimum and maximum specification.

Reason For Change:

To facilitate improvement in manufacturing capability.

Impact of the change (positive or negative) on fit, form, function & reliability:

This datasheet change does not impact the fit, form, function, or reliability of the LTC2979.

Product Identification *(this section will describe how to identify the changed material)*

Product shipped after effectivity date will be tested to the new limits.

Can be identified with date code and lot traceability identification.

Summary of Supporting Information:

Changes will be reflected on the new product datasheet. See changes on Electrical Characteristics table on page 5.

Supporting Documents

Attachment 1: Type: Datasheet Specification Comparison

ADI_PCN_22_0088_Rev_-LTC2979_Datasheet Marked-up_Pages.pdf

For questions on this PCN, please send an email to the regional contacts below or contact your local ADI sales representatives.

Americas:
PCN_Americas@analog.com

Europe:
PCN_Europe@analog.com

Japan:
PCN_Japan@analog.com

Rest of Asia:
PCN_ROA@analog.com

Appendix A - Affected ADI Models

Added Parts On This Revision - Product Family / Model Number (2)

LTC2979 / LTC2979CY#PBF	LTC2979 / LTC2979Y#PBF			
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Appendix B - Revision History

Rev	Publish Date	Effectivity Date	Rev Description
Rev. -	27-Apr-2022	30-Jul-2022	Initial Release

Analog Devices, Inc.

DocId:8869 Parent DocId:None Layout Rev:8

ELECTRICAL CHARACTERISTICS

The ● denotes the specifications which apply over the full operating temperature range, otherwise specifications are at $T_J = 25^\circ\text{C}$. $V_{\text{DD}33} = 3.3\text{V}$, $V_{\text{IN_SNS}} = 12\text{V}$, $V_{\text{DD}25}$ and REF pins floating, unless otherwise indicated. (Notes 2, 3)

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	UNITS
$V_{\text{IN_SNS}}$ Input Characteristics						
$V_{\text{VIN_SNS}}$	$V_{\text{IN_SNS}}$ Input Voltage Range		●	0	15	V
$R_{\text{VIN_SNS}}$	$V_{\text{IN_SNS}}$ Input Resistance		●	70	90	$\text{k}\Omega$
TUE _{VIN_SNS}	VIN_ON, VIN_OFF Threshold Total Unadjusted Error	$3\text{V} \leq V_{\text{VIN_SNS}} \leq 8\text{V}$	●		± 2.0	% of Reading
		$V_{\text{VIN_SNS}} > 8\text{V}$	●		± 1.0	% of Reading
	READ_VIN Total Unadjusted Error	$3\text{V} \leq V_{\text{VIN_SNS}} \leq 8\text{V}$	●		± 1.5	% of Reading
		$V_{\text{VIN_SNS}} > 8\text{V}$	●		± 1.0	% of Reading
Temperature Sensor Characteristics						
TUE_TS	Total Unadjusted Error				± 1	$^\circ\text{C}$
$V_{\text{OUT_EN}}$ Enable Output ($V_{\text{OUT_EN}}[3:0]$) Characteristics						
I _{VOUT_ENn}	Output Sinking Current	Strong Pull-Down Enabled, $V_{\text{VOUT_EN}n} = 0.4\text{V}$	●	3	5	8 mA
		Weak Pull-Down Enabled, $V_{\text{VOUT_EN}n} = 0.4\text{V}$	●	33	50	60 μA
	Output Leakage Current	Internal Pull-Up Disabled, $0\text{V} \leq V_{\text{VOUT_EN}n} \leq 6\text{V}$	●	28	43	$\pm 1 \mu\text{A}$
V _{VOUT_VALID}	Minimum $V_{\text{DD}33}$ when $V_{\text{VOUT_EN}n}$ Valid	$V_{\text{VOUT_EN}n} \leq 0.4\text{V}$	●		1.1	V
$V_{\text{OUT_EN}}$ Enable Output ($V_{\text{OUT_EN}}[7:4]$) Characteristics						
I _{VOUT_ENn}	Output Sinking Current	Strong Pull-Down Enabled, $V_{\text{VOUT_EN}n} = 0.1\text{V}$	✗	✗	6	✗ mA
	Output Leakage Current	$0\text{V} \leq V_{\text{VOUT_EN}n} \leq 6\text{V}$	●		± 1	μA
V_{IN} Enable Output ($V_{\text{IN_EN}}$) Characteristics						
I _{VIN_EN}	Output Sinking Current	$V_{\text{VIN_EN}} = 0.4\text{V}$	●	3	5	8 mA
	Leakage Current	Internal Pull-Up Disabled, $0\text{V} \leq V_{\text{VIN_EN}} \leq 6\text{V}$	●		± 1	μA
V _{VOUT_VALID}	Minimum $V_{\text{DD}33}$ when $V_{\text{VOUT_EN}n}$ Valid	$V_{\text{VOUT_EN}n} \leq 0.4\text{V}$	●		1.1	V
EEPROM Characteristics						
Endurance	(Notes 10, 11)	$0^\circ\text{C} < T_J < 85^\circ\text{C}$ During EEPROM Write Operations	●	10,000		Cycles
Retention	(Notes 10, 11)	$T_J < 105^\circ\text{C}$	●	20		Years
t _{MASS_WRITE}	Mass Write Operation Time (Note 12)	STORE_USER_ALL, $0^\circ\text{C} < T_J < 85^\circ\text{C}$ During EEPROM Write Operations	●	440	4100	ms
Digital Inputs SCL, SDA, CONTROL0, CONTROL1, WDI/RESETB, FAULTB00, FAULTB01, FAULTB10, FAULTB11, WP						
V _{IH}	High Level Input Voltage		●	2.1		V
V _{IL}	Low Level Input Voltage		●		1.5	V
V _{HYST}	Input Hysteresis			20		mV
I _{LEAK}	Input Leakage Current	$0\text{V} \leq V_{\text{PIN}} \leq 5.5\text{V}$, SDA, SCL, CONTROL n Pins Only	●		± 2	μA
		$0\text{V} \leq V_{\text{PIN}} \leq V_{\text{DD}33} + 0.3\text{V}$, FAULTB z n, WDI/RESETB, WP Pins Only	●		± 2	μA